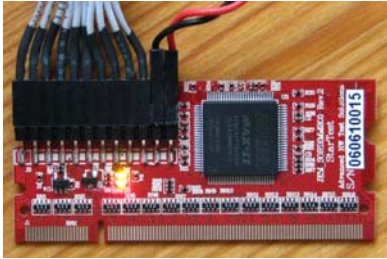
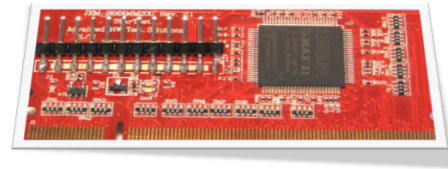


JEM_DIMM/SODIMM

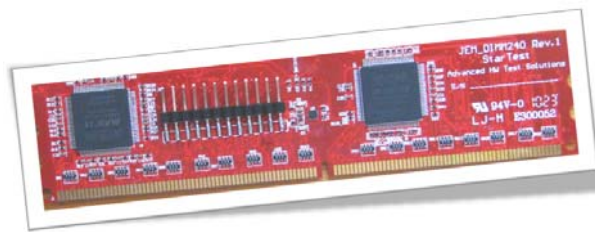
JTAG External Modules for DIMM/SODIMM Socket Test



JEM_SORDIMM200 Module



JEM_SODIMM200 Module



JEM_DIMM240 Module

The **StarTest JEM_DIMM/SODIMM** modules main features are:

- ✓ Performs both Interconnect and Cluster tests for a wide range of DIMM/SODIMM DDR2 and DDR3 memory sockets
- ✓ Supports both external (via header) and in-circuit (via DIMM/SODIMM socket) TAP connection
- ✓ Tests for opens all PWR and GND pins of the DIMM/SODIMM memory sockets
- ✓ Each I/O pin is independently controlled for sense, drive, bi-directional, and tri-state function
- ✓ Keyed flat connector compatibility
- ✓ Hot Swap: each module may be connected/disconnected between tests without switching power off
- ✓ Equipped with the JTAG/IEEE 1149.1 Test Access Port (TAP)
- ✓ Supplied software contains BSDL file of the module
- ✓ Full compatibility with the following JTAG vendor ATPG and Runner platforms:

- ❖ Flynn Systems' **onTAP** Series 4000
- ❖ Corelis' **ScanExpress**
- ❖ JTAG Technologies' **ProVision**
- ❖ Asset' **ScanWorks**
- ❖ Goepel' **CASCON**
- ❖ XJTAG' **XJRunner**



innovation in boundary-scan



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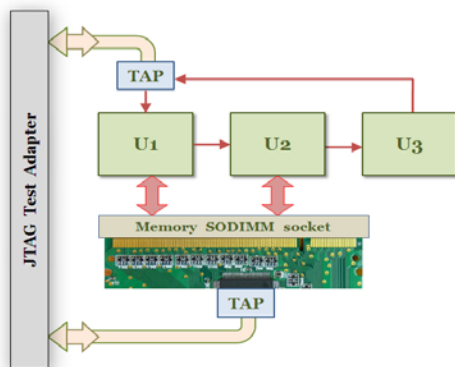
STARTTEST
Advanced HW Test Solutions

JEM_DIMM/SODIMM

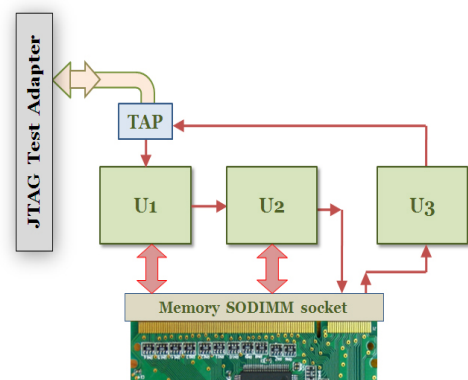
- ✓ Supports the wide range of DIMM, microDIMM, SODIMM, SOCDIMM, and SORDIMM memory socket formats (consult [StarTest](#) for additional sockets):

Module Name	Ordering Part Number	Family Name
■ 72 pin SODIMM	JEM_SODIMM72	SODIMM
■ 100 pin SODIMM	JEM_SODIMM100	SODIMM
■ 144 pin SODIMM	JEM_SODIMM144	SODIMM
■ 200 pin SODIMM	JEM_SODIMM200	SODIMM
■ 204 pin SODIMM	JEM_SODIMM204	SODIMM
■ 200 pin SORDIMM	JEM_SORDIMM200	SODIMM
■ 200 pin SOCDIMM	JEM_SOCDIMM200	SODIMM
■ 168 pin DIMM	JEM_DIMM168	DIMM
■ 184 pin DIMM	JEM_DIMM184	DIMM
■ 240 pin DIMM	JEM_DIMM240	DIMM
■ 240 pin UDIMM	JEM_UDIMM240	DIMM
■ 244 pin miniDIMM	JEM_mDIMM244	miniDIMM
■ 144 pin microDIMM	JEM_uDIMM144	microDIMM
■ 172 pin microDIMM	JEM_uDIMM172	microDIMM
■ 214 pin microDIMM	JEM_uDIMM214	microDIMM
■ 240 pin VLP RDIMM	JEM_VLP-RDIMM240	VLP-DIMM
■ 240 pin VLP DIMM	JEM_VLP-DIMM240	VLP-DIMM
■ 200 pin VLP SORDIMM	JEM_VLP-SORDIMM200	VLP-SORDIMM
■ 244 pin VLP mini-RDIMM	JEM_VLP-mRDIMM244	VLP-miniDIMM
■ 244 pin VLP miniDIMM	JEM_VLP-mDIMM244	VLP-miniDIMM
■ CompactFlash Module	JEM_FlashCard	(form factor- upon demand)

For many designs, JTAG test has adequate access to on-board signals, but signals that go off the board often cannot be tested. By adding JTAG access to memory socket off-board signals, a **JEM_DIMM/SODIMM** module increases the board's fault coverage, possibly reducing the need for developing alternative tests to reach the required test coverage level. The **JEM_DIMM/SODIMM** module provides a number of JTAG accessible individually controlled test channels that can be used to control and observe signals that go off the board.



*DIMM/SODIMM JTAG test setup
with external TAP cable*



*DIMM/SODIMM JTAG completely in-circuit test setup
without external TAP cable*

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